

RELIABILITY DATA

LT1032

4/30/2003

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
CERDIP	319	8512	9339	953.25	1
PLASTIC DIP	127	9025	9706	924.13	0
	446			1,877.39	1

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
PLASTIC DIP	700	9207	9849	14.40	0
SOIC/SOT/MSOP	1,413	9109	0047	33.60	1
	2,113			48.00	2

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
CERDIP	79	8512	8702	2.14	0
PLASTIC DIP	469	8644	0119	100.34	0
SOIC/SOT/MSOP	435	9109	0020	50.30	0
	983			152.77	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
CERDIP	15	8702	8702	0.23	0
PLASTIC DIP	268	8644	9849	57.60	0
SOIC/SOT/MSOP	580	9109	0047	61.60	0
	863			119.43	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 2.16 FITS

(3) Mean Time Between Failures in Years = 52,813

Note: 1 FIT = 1 Failure in One Billion Hours.